

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. <b>247579US2TTCRD CONT</b>		SERIAL NO. <b>New Application</b>	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT <b>Yoshiaki SAITO, et al.</b>			
				FILING DATE <b>Herewith</b>		GROUP <b>Unassigned</b>	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
HN	AA	6,430,085	8-6-2002	N. D. RIZZO	365	173	_____
HN	AB	6,556,473	4-29-2003	SAITO et al.	365	158	_____
HN	AC	6,639,830	10-28-2003	C. HEIDE	365	158	_____
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES                  NO		
	AO						
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
HN	AW	J.S. MOODERA, et al., J. Appl. Phys., vol. 79, no. 8, pages 4724-4729, "FERROMAGNETIC-INSULATOR-FERROMAGNETIC TUNNELING: SPIN-DEPENDENT TUNNELING AND LARGE MAGNETORESISTANCE IN TRILAYER JUNCTIONS (INVITED)", April 15, 1996					
HN	AX	F. MONTAIGNE, et al., Applied Physics Letters, vol. 73, no. 19, pages 2829-2831, "ENHANCED TUNNEL MAGNETORESISTANCE AT HIGH BIAS VOLTAGE IN DOUBLE-BARRIER PLANAR JUNCTIONS", November 9, 1998					
HN	AY	L.F. SCHELP, et al., Physical Review B, vol. 56, no. 10, pages R-5747-R5750, "SPIN-DEPENDENT TUNNELING WITH COULOMB BLOCKADE", September 1, 1997					
HN	AZ	Y. SAITO, et al., Jpn. J. Appl. Phys., vol. 39, no. 10B, pages L-1035-L1038, "CORRELATION BETWEEN BARRIER WIDTH, BARRIER HEIGHT, AND DC BIAS VOLTAGE DEPENDENCIES ON THE MAGNETORESISTANCE RATIO IN Ir-Mn EXCHANGE BIASED SINGLE AND DOUBLE TUNNEL JUNCTIONS", October 15, 2000				<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <b>HIEN NGUYEN</b>					Date Considered <b>6/25/04</b>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							